

P1445

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Type of Project: Revision to IEEE Standard 1445-1998

PAR Request Date: 17-Jun-2015

PAR Approval Date: 03-Sep-2015

PAR Expiration Date: 31-Dec-2019

Status: PAR for a Revision to an existing IEEE Standard

Root Project: 1445-1998

1.1 Project Number: P1445

1.2 Type of Document: Standard

1.3 Life Cycle: Full Use

2.1 Title: Standard for Digital Test Interchange Format (DTIF)

Changes in title: ~~IEEE~~ Standard for Digital Test Interchange Format (DTIF)

3.1 Working Group: Diagnostic and Maintenance Control Working Group (SASB/SCC20/DMC_WG)

Contact Information for Working Group Chair

Name: John Sheppard

Email Address: jsheppa2@gmail.com

Phone: 443-851-2809

Contact Information for Working Group Vice-Chair

None

3.2 Sponsoring Society and Committee: IEEE-SASB Coordinating Committees/SCC20 - Test and Diagnosis for Electronic Systems (SASB/SCC20)

Contact Information for Sponsor Chair

Name: Mike Seavey

Email Address: mike.seavey@gmail.com

Phone: 224-558-7347

Contact Information for Standards Representative

None

4.1 Type of Ballot: Individual

4.2 Expected Date of submission of draft to the IEEE-SA for Initial Sponsor Ballot: 06/2017

4.3 Projected Completion Date for Submittal to RevCom: 08/2018

5.1 Approximate number of people expected to be actively involved in the development of this project: 10

5.2 Scope: This standard defines digital automated test program generator (DATPG) output data formats and informational content for unit under test (UUT) models, stimulus and response patterns, fault dictionaries, and diagnostic probing. These output provide a standard exchange format to automatic test equipment (ATE).

Changes in scope: This standard ~~will defines defined~~ digital ~~the automated test program set generator (DATPG) output data embodied formats in and a informational number content of for ASCH unit files under for test stimulus (UUT) models, stimulus and response patterns, fault dictionaries, and diagnostics diagnostic of probing. digital These systems output for provide use a on standard digital exchange Automatic format Test to Systems automatic test equipment (ATE).~~

5.3 Is the completion of this standard dependent upon the completion of another standard: No

5.4 Purpose: This standard is to be used as the standard definition of DATPG output formats and informational content.

Changes in purpose: This standard ~~will is develop a definition of digital test information for digital test systems to cover be UUT used Model, as stimulus/response, the fault standard dictionary, definition probe data, and other forms of data. DATPG Any output existing formats defacto and standards informational will be given precedenee content.~~

5.5 Need for the Project: This active Digital Instrumentation related standard has been cycling through the Re-affirmation process the last several years. Re-affirmation is no longer an option, and the standard is Required by ATE industry.

5.6 Stakeholders for the Standard: The stake holders will include end-product users of Digital instrumentation who need to combine disparate

software-controlled products on a variety of scales and produce archive-quality documentation.

Specifically,

Military

Aerospace

Commercial aviation

Intellectual Property

6.1.a. Is the Sponsor aware of any copyright permissions needed for this project?: Yes

If yes please explain: Teradyne Corporation Owns the rights to LASAR, the basis of this standard. A LOA is in process as the original LOA from the 1990's cannot be located.

6.1.b. Is the Sponsor aware of possible registration activity related to this project?: No

7.1 Are there other standards or projects with a similar scope?: No

7.2 Joint Development

Is it the intent to develop this document jointly with another organization?: No

8.1 Additional Explanatory Notes (Item Number and Explanation): The adoption by IEC will be through the IEEE/IEC Dual Logo agreement